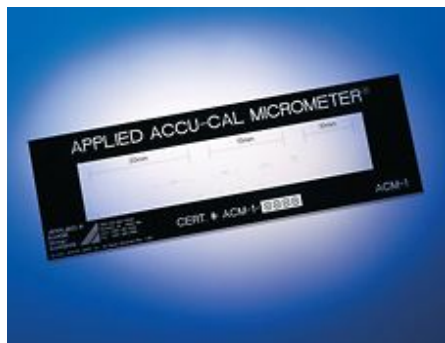


[All Products](#) / [Test Targets](#) / [Image Analysis & Stage Micrometers](#)

Reticle Calibration Stage Micrometer



- Features a Series of "H" Shaped Fiducial Images
- Image Sizes from 0.1 to 20mm
- Available with NIST Traceable Data

Common Specifications

Physical & Mechanical Properties

Dimensions (mm):	25.4 x 76.2 ±0.100	Thickness (mm):	1.52 ±0.100
Pattern Length (mm):	0.1 - 20.0		

Optical Properties

Surface Quality:	60-40		
Substrate:	Durable Chromium Coating on Glass	Optical Density OD (Average):	>2.0

Technical Information

Products

NIST Certification	Stock Number	Price	Buy
No	#59-280	€413,03 Volume Pricing	2 In Stock
Yes	#59-281	€757,05 Volume Pricing	3 In Stock



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